

# Metastable Impact Electron Emission Microscopy: Principles and Applications

Y. Suchorski<sup>a</sup> and G. Lilienkamp<sup>b</sup>

<sup>a</sup>*Chemisches Institut, Otto-von-Guericke-Universität Magdeburg,  
Universitätsplatz 2, D-39106 Magdeburg, Germany*

<sup>b</sup>*Institut für Physik und Physikalische Technologien, Technische Universität Clausthal,  
Leibnizstr. 4, D-38678 Clausthal-Zellerfeld, Germany*

The Metastable Impact Electron Emission Microscopy (MIEEM) provides chemical contrast at the surface by electrons emitted due to the metastable He\*-atom (<sup>3</sup>S) impact. The MIEEM imaging mode, realized by combination of the He\* source with the Spectroscopic Low Energy Electron Microscope (SpecLEEM), achieved a spectral resolution < 1 eV and a spatial resolution ~200 nm at 10-20 sec of image acquisition time. In this way a reliable monitoring of spatio-temporal processes within the visual field of view of ca. 50 µm diameter became possible. Few applications will be presented: a study of the chemical composition of insulating islands appearing on La doped SrTiO<sub>3</sub> (100) surfaces [1] as well as the first successful employment of MIEEM for probing the spatial distribution of adsorbates on metal surfaces and for the *in situ* imaging of surface reactions [2]. The spectroscopic identification of the reactants during the propagation of the reaction fronts allows to trace the reaction-caused redistribution of the potassium used as an reaction-additive. The redistribution of potassium is explained in terms of the chemically assisted uphill diffusion.

[1] Han Wei, W. Maus-Friedrichs, G. Lilienkamp, V. Kempster, J. Helmbold, K. Gömann and G. Borchardt, *Journal of Electroceramics*, 8 (2002) 221.

[2] G. Lilienkamp, Han Wei, W. Maus-Friedrichs, V. Kempster, H. Marbach, S. Guenther and Y. Suchorski, *Surf. Sci.* 532-535 (2003) 132.